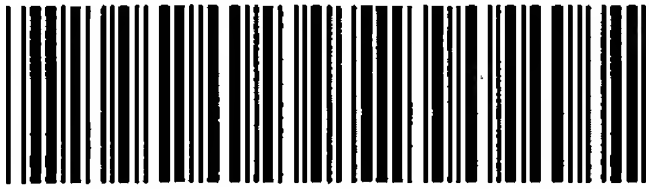


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/617,826	CHEN ET AL.	
	Examiner	Art Unit	
	Leon J. Harper	2166	

SEARCHED			
Class	Subclass	Date	Examiner
707	104.1, 200, 100 1, 4, 10	1/4/2005	LJH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
consulted with K. pham about prior art	1/5/2005	LJH